


Schedule of Accreditation

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United Kingdom Accreditation Service

2 Pine Trees, Chertsey Lane, Staines-upon-Thames, TW18 3HR, UK

 <p>UKAS TESTING</p> <p>4290</p> <p>Accredited to ISO/IEC 17025:2017</p>	<p>Global CS Center of Samsung Electronics Co Ltd</p> <p>Issue No: 045 Issue date: 06 February 2026</p>	
	<p>(Maetan Dong) 129 Samsung-ro Yeongtong-Gu Suwon-Si Gyeonggi-Do 16677 Korea</p>	<p>Contact: Mr Hae Kuen Song Tel: +82 (0)10 9530 1527 Fax: +82 (0)31 277 7753 E-Mail: hkuen.song@samsung.com Website: www.samsung.com</p>
<p>Testing performed by the Organisation at the locations specified below</p>		

Locations covered by the organisation and their relevant activities

Laboratory locations:

Location details	Activity	Location code
<p>Address R3 Samsung Electronics Co Ltd (Maetan Dong) 129 Samsung-ro Yeongtong-Gu Suwon-Si Gyeonggi-Do 16677 Korea</p> <p>Local contact Mr Young Ju Ryu Tel: + (82)-(0)31-277-7763 Fax: + (82)-(0)31-277-7753 Email: yj14.ryu@samsung.com</p>	<p>Testing EMC</p>	R3
<p>Address R4 Samsung Electronics Co Ltd (Maetan Dong) 129 Samsung-ro Yeongtong-Gu Suwon-Si Gyeonggi-Do 16677 Korea</p> <p>Local contact Mr Young Ju Ryu Tel: + (82)-(0)31-277-7763 Fax: + (82)-(0)31-277-7753 Email: yj14.ryu@samsung.com</p>	<p>Testing EMC</p>	R4
<p>Address R4 Samsung Electronics Co Ltd (Maetan Dong) 129 Samsung-ro Yeongtong-Gu Suwon-Si Gyeonggi-Do 16677 Korea</p> <p>Local contact Mr Joung Woo Kang Tel: + (82)-(0)31-277-7782 Fax: + (82)-(0)31-277-7753 Email: jw01.kang@samsung.com</p>	<p>Testing Battery Performance, Safety and Lifetime Testing</p>	R4



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Location details	Activity	Location code	
Address R4 Samsung Electronics Co Ltd (Maetan Dong) 129 Samsung-ro Yeongtong-Gu Suwon-Si Gyeonggi-Do 16677 Korea	Local contact Mr Jaeyu Kim Tel: + (82)-(0)10-4075-9112 Fax: + (82)-(0) 31-277-1375 Email: jy1627.kim@samsung.com	Testing: DTV	R4
Address R5 Samsung Electronics Co Ltd (Maetan 3-Dong) 129 Samsung-ro Yeongtong-Gu Suwon-Si Gyeonggi-Do 16677 Korea	Local contact Mr Young Ju Ryu Tel: + (82)-(0)31-277-7763 Fax: + (82)-(0)31-277-7753 Email: yj14.ryu@samsung.com	Testing: EMC	R5



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DETAIL OF ACCREDITATION

Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
Audio-Video Equipment Computers and Peripherals Digital IT Equipment Office Equipment - Electrical Radio and TV Equipment Alarm systems Home Appliances ISM Equipment	1 EMC Tests 1.1 Conducted Emissions 150 kHz to 30 MHz excluding discontinuous interference	EN 55011:2007+A2:2007 EN 55011:2009 EN 55011:2009+A1:2010 EN 55011:2016 EN 55011:2016+A1:2017 EN 55011:2016+A11:2020 EN 55011:2016+A2:2021 CISPR 11:2009 CISPR 11:2010 CISPR 11:2015 CISPR 11:2017 CISPR 11:2019 AS/NZS CISPR 11:2004 AS/NZS CISPR 11:2011 AS CISPR 11:2017 AS CISPR 11:2017+A1:2020 SANS 211:2010	R4, R5
		EN 55013:2001+A1:2003+A2:2006 EN 55013:2013 CISPR 13:2009 CISPR 13:2015 AS/NZS CISPR 13:2004 AS/NZS CISPR 13:2012	R4
		EN 55014-1:2006+A1:2009 EN 55014-1:2006+A1:2009+A2:2011 EN 55014-1:2017 EN 55014-1:2017+A11:2020 EN IEC 55014-1:2021 CISPR 14-1:2011 CISPR 14-1:2020	R3, R4, R5



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
As listed on Page 3	1 EMC Tests (continued) 1.1 Conducted Emissions 150 kHz to 30 MHz excluding discontinuous interference (continued)	AS/NZS CISPR 14.1:2003 AS/NZS CISPR 14.1:2010 AS/NZS CISPR 14.1:2013 AS CISPR 14.1:2018 AS/NZS CISPR 14.1:2021 SANS 214-1:2020 EN 55022:2006+A1:2007 EN 55022:2010+AC1:2011 CISPR 22:2008 AS/NZS CISPR 22:2006 AS/NZS CISPR 22:2009 AS/NZS CISPR 22:2009+A1 EN 55032:2012+AC1:2013 EN 55032:2015 EN 55032 :2015+AC :2016 EN 55032:2015+A11:2020 EN 55032:2015+A11:2020+A1:2020 CISPR 32:2012 CISPR 32:2015 CISPR 32:2015+A1:2019 AS/NZS CISPR 32:2013 AS/NZS CISPR 32:2015 AS/NZS CISPR 32:2015+A1:2020 SANS 2332:2017 IS CISPR 32:2015	R3, R4, R5
	1.2 Radiated Emissions E-field: 30 MHz to 18 GHz H-field: 9 kHz to 30 MHz	EN 55011:2007+ A2:2007 EN 55011:2009 EN 55011:2009+A1:2010 EN 55011:2016 EN 55011:2016+A1:2017 EN 55011:2016+A11:2020 EN 55011:2016+A2:2021	R4, R5



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As listed on Page 3	1 EMC Tests (continued)		
	1.2 Radiated Emissions (continued) E-field: 30 MHz to 18 GHz H-field: 9 kHz to 30 MHz	CISPR 11:2009 CISPR 11:2010 CISPR 11:2015 CISPR 11:2017 CISPR 11:2019 AS/NZS CISPR 11:2004 AS/NZS CISPR 11:2011 AS CISPR 11:2017 AS CISPR 11:2017+A1:2020 SANS 211:2010	R4, R5
	E-field: 30 MHz to 3 GHz	EN 55013:2001+A1:2003+A2:2006 EN 55013:2013 CISPR 13:2009 CISPR 13:2015 AS/NZS CISPR 13:2004 AS/NZS CISPR 13:2012	R4
	E-field: 30 MHz to 6 GHz H-field : 9 kHz to 30 MHz	EN 55014-1:2006+A1:2009 EN 55014-1:2006+A1:2009+A2:2011 EN 55014-1:2017 EN 55014-1:2017+A11:2020 EN IEC 55014-1:2021 CISPR 14-1:2011 CISPR 14-1:2020 AS/NZS CISPR 14.1:2010 AS/NZS CISPR 14.1:2013 AS CISPR 14.1:2018 AS/NZS CISPR 14.1:2021 SANS 214-1:2020	R3, R4, R5



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As listed on Page 3	1 EMC Tests (continued) 1.3 Disturbance Power 30 MHz to 300 MHz	CISPR 14-1:2011 CISPR 14-1:2020 AS/NZS CISPR 14.1:2013 AS CISPR 14.1:2018 AS/NZS CISPR 14.1:2021 SANS 214-1:2020	
	1.4 Discontinuous Emissions Clicks 150 kHz to 30 MHz	EN 55014-1:2006+A1:2009 EN 55014-1:2006+A1:2009+ A2: 2011 EN 55014-1:2017 EN 55014-1:2017+A11:2020 EN IEC 55014-1:2021 CISPR 14-1:2011 CISPR 14-1:2020 AS/NZS CISPR 14.1:2003 AS/NZS CISPR 14.1:2010 AS/NZS CISPR 14.1:2013 AS CISPR 14.1:2018 AS/NZS CISPR 14.1:2021 SANS 214-1:2020	R4
	1.5 Current Harmonics	EN 61000-3-2:2006+A1:2009 EN 61000-3-2:2006+A1:2009+ A2:2009 EN 61000-3-2:2014 EN IEC 61000-3-2:2019 EN IEC 61000-3-2:2019+A1:2021 EN IEC 61000-3-2:2019 +A1:2021+A2:2024 IEC 61000-3-2:2009 IEC 61000-3-2:2015 IEC 61000-3-2:2018 IEC 61000-3-2 :2018+A1:2020 IEC 61000-3-2:2018 +A1:2020+A2:2024 SANS 61000-3-2:2009	R3, R4, R5



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As listed on Page 3	1 EMC Tests (continued) 1.6 Voltage fluctuations and Flicker	EN 61000-3-3:1995 A1:1998+ A2:2005 EN 61000-3-3:2008 EN 61000-3-3:2013 EN 61000-3-3:2013+A1:2019 EN 61000-3-3:2013+A2:2021 IEC 61000-3-3:2008 IEC 61000-3-3:2013 IEC 61000-3-3:2013+A2:2021 SANS 61000-3-3:2009	R3, R4, R5
	1.7 Electrostatic Discharge 2 kV to 16 kV	EN 61000-4-2:1995+A1:1998+ A2:2001 EN 61000-4-2:2009 IEC 61000-4-2:2001 IEC 61000-4-2:2008 SANS 61000-4-2:2009	R3, R4, R5
	1.8 Radiated Immunity 80 MHz to 6 GHz 3V/m (R3, R4, R5) 80 MHz to 6 GHz 10 V/m (R3, R5) EN 60601-1-2 Table 9 (R5) IEC 60601-1-2 Table 9 (R5)	EN 61000-4-3:1996 EN 61000-4-3:2002+A1:2002 EN 61000-4-3:2006+A1:2008 EN 61000-4-3:2006+A1:2008+ A2:2010 EN IEC 61000-4-3:2020 IEC 61000-4-3:2002 IEC 61000-4-3:2006 IEC 61000-4-3:2008 IEC 61000-4-3:2010 SANS 61000-4-3:2008	R3, R4, R5



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
As listed on Page 3	1 EMC Tests (continued) 1.9 Fast Transient/Burst Immunity 0.25 kV to 4.0 kV	EN 61000-4-4:1995+A1:2001+ A2:2001 EN 61000-4-4:2004 EN 61000-4-4:2004+A1:2010 EN 61000-4-4:2012 IEC 61000-4-4:1995+A1:2000+ A2:2001 IEC 61000-4-4:2004 IEC 61000-4-4:2012 SANS 61000-4-4:2011	R3, R4, R5
	1.10 Surge 0.5 kV to 4 kV	EN 61000-4-5:1995+A1:2001 EN 61000-4-5:2006 EN 61000-4-5:2014 EN 61000-4-5:2014+A1:2017 IEC 61000-4-5:2005 IEC 61000-4-5:2014 IEC 61000-4-5:2014+A1:2017 SANS 61000-4-5:2006	R3, R4, R5
	1.11 Conducted Immunity 100 kHz to 250 MHz 85 W max	EN 61000-4-6:1996+A1:2001 EN 61000-4-6:2007 EN 61000-4-6: 2009 EN 61000-4-6: 2014 EN 61000-4-6:2014+AC:2015 EN IEC 61000-4-6:2023 IEC 61000-4-6:2003 IEC 61000-4-6:2004 IEC 61000-4-6:2006 IEC 61000-4-6:2008 IEC 61000-4-6:2013 IEC 61000-4-6:2023 SANS 61000-4-6:2017	R3, R4, R5



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As listed on Page 3	1 EMC Tests (continued) 1.12 Power-Frequency Magnetic Fields (Immunity) Frequency: 50 Hz to 60 Hz Field strength: up to 100 A/m	EN 61000-4-8:1993+A1:2001 EN 61000-4-8:2010 IEC 61000-4-8:2001 IEC 61000-4-8:2009	R5
	1.13 Voltage Dips and Interruptions Max inrush capability: R3 425A R4 695A R5 509A	EN 61000-4-11:1994+A1:2001 EN 61000-4-11:2004 EN 61000-4-11:2004+A1:2017 EN IEC 61000-4-11:2020 IEC 61000-4-11:1994 IEC 61000-4-11:2004 SANS 61000-4-11:2005	R3, R4, R5
	1.14 Generic and Product Specific Standards These Generic and Product specific tests are included in this Schedule, but limited to those referred basic standards that are explicitly listed in Sections 1.1 to 1.14	EN 50130-4:1995+A1:1998+A2:2003 EN 61000-6-1:2007 IEC 61000-6-1:2016 EN IEC 61000-6-1:2019 EN 61000-6-2:2005 EN IEC 61000-6-2:2019 IEC 61000-6-2:2016 EN 61000-6-3:2007 EN 61000-6-3:2007+A1:2011 EN IEC 61000-6-3:2021 IEC 61000-6-3:2020 EN 61000-6-4:2007 EN 61000-6-4:2007+A1:2011 EN IEC 61000-6-4:2019 IEC 61000-6-4:2018 EN IEC 61000-6-8:2020 IEC 61000-6-8:2020 EN 61204-3:2000	R3, R4 R3, R4, R5 R3, R4, R5



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
As listed on Page 3	<p>1 EMC Tests (continued)</p> <p>1.15 Generic and Product Specific Standards</p> <p>These Generic and Product specific tests are included in this Schedule, but limited to those referred basic standards that are explicitly listed in Sections 1.1 to 1.14</p>	<p>EN 301 489-17 V1.2.1 EN 301 489-17 V2.1.1 EN 301 489-17 V2.2.1 EN 301 489-17 V3.1.1 EN 301 489-17 V3.2.0 EN 301 489-17 V3.2.4 EN 301 489-17 V3.3.1 EN 301 489-19 V2.1.0 EN 301 489-19 V2.1.1 EN 301 489-19 V2.2.1 EN 301 489-23 V1.4.1 EN 301 489-23 V1.5.1 EN 301 489-24 V1.4.1 EN 301 489-24 V1.5.1 EN 301 489-26 V2.3.2 EN 301 489-33 V2.2.1 EN 301 489-50 V1.2.1 EN 301 489-50 V2.1.1 EN 301 489-50 V2.2.1 EN 301 489-50 V2.3.1 EN 301 489-52 V1.1.0 EN 301 489-52 V2.0.2 EN 301 489-52 V1.2.1 EN 301 489-52 V1.3.1 EN 303 386 V1.6.1 EN 303 446-1 V1.1.0 EN 303 446-1 V1.2.1</p> <p>QCVN 18:2022/BTTTT QCVN 86:2019/BTTTT QCVN 96:2015/BTTTT QCVN 103:2016/BTTTT QCVN 112:2017/BTTTT QCVN 118:2018/BTTTT</p>	<p>R3, R4, R5</p> <p>R5 R3 R3 R3</p> <p>R3, R5 R3, R5</p> <p>R3 R4</p>



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
	<p><u>EMC Facilities</u></p> <p><u>In R3 location:</u> Fully Anechoic Chamber, 7.9 m x 4.3 m x 4.2 m, Fully Anechoic Chamber, 7.9 m x 4.0 m x 3.3 m, 10m Semi-Anechoic Chamber, 19.6 m x 12.4 m x 7.5 m Shielded Room No.1 (EFT/CS/Harmonic), 7.0 m x 5.4 m x 3.3 m, Shielded Room No.2 (CE), 7.0 m x 5.5 m x 3.3 m Shielded Room No.3 (Surge/ESD/Dip), 7.0 m x 5.4 m x 3.3 m,</p> <p><u>In R4 location:</u> Fully Anechoic Chamber 7.9 m x 4.6 m x 3.3 m (RS/S5/S6) , 10m Semi-Anechoic Chamber (2ea) 25.6 m x 18.4 m x 11.1m 3m Semi-Anechoic Chamber 12.1 m x 10.0 m x 6.9 m, Shielded Room No 1 (CE/ /DD), 9.1 m x 4.6 m x 3.3 m Shielded Room No.2 (Ant. Terminal/Surge/Dip), 7.9 m x 4.6 m x 3.3 m Shielded Room No.3 (ESD/ Harmonics), 7.9 m x 4.6 m x 3.3 m Shielded Room No.4 (DP), 10.9 m x 4.9 m x 3.3 m Shielded Room No.5 (CS/EFT), 10.9 m x 4.9 m x 3.3 m Shield Room Jacky Room (S3), 4.3 m x 4.9 m x 3.3 m</p> <p>Max EUT size: 1.5 m x 1.8 m x 1.5 m Max EUT weight: 2000 kg</p> <p>Power supplies available: 1phase: Up to AC 270 V, 20 to 5 kHz, 63 A 3 phase: Up to AC 470 V, 20 to 5 kHz, 48 A</p> <p><u>In R5 location :</u> Fully Anechoic Chamber (RS), 9.2 m x 4.8 m x 4.3 m 10m Semi-Anechoic Chamber (2ea), 21.0 m x 13.0 m x 10.0 m Shielded Room No.4 (ESD/CS/EFT), 4.3 m x 6.4 m x 3.3 m Shielded Room No.5 (Harmonics/CE/SURGE/VDI), 8.1 m x 4.6 m x 3.3</p> <p>Power supplies available: 1 phase: up to AC 270 V, 20 to 5 kHz, 63 A 3 phase: up to AC 470 V, 20 to 5 kHz, 48 A</p>		



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
Mobile Phone Batteries, Laptop, Notebook, Portable Computer Batteries	2 Environmental Tests (non explosive items) and associated Electrical and Teardown Tests	CTIA Certification Requirements for Battery System Compliance to : IEEE 1725 :2021: Rechargeable Batteries for Mobile Phones	
	2.1 Ambient Consideration	Clause 5.9, IEEE 1725:2021	R4
	2.2 Thermal Protection Design	Clause 5.14, IEEE 1725:2021	R4
	2.3 Action, Thermal Protection	Clause 5.15, IEEE 1725:2021	R4
	2.4 External Mechanical Force	Clause 5.23, IEEE 1725:2021	R4
	2.5 Cell Block Overvoltage Protection	Clause 5.46, IEEE 1725:2021	R4
	2.6 Cell Block Undervoltage Protection	Clause 5.47, IEEE 1725:2021	R4
	2.7 Pack Overvoltage Protection, Verification and Testing	Clause 5.51, IEEE 1725:2021	R4
	2.8 Pack Drop Test 1.5 m drop height Surface: concrete	Clause 5.52, IEEE 1725:2021	R4
	2.9 Input Surge Excluding ISO-7637-2	Clause 6.2, IEEE 1725:2021	R4
	2.10 Overvoltage	Clause 6.3, IEEE 1725:2021	R4
	2.11 Overcurrent	Clause 6.4, IEEE 1725:2021	R4
	2.12 Fault Isolation and Tolerance	Clause 6.7, IEEE 1725:2021	R4
	2.13 Pack Identification	Clause 6.9, 6.10, IEEE 1725:2021	R4



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
Mobile Phone Batteries Laptop, Notebook, Portable Computer Batteries (continued)	2 Environmental Tests (non explosive items) and associated Electrical and Teardown Tests (continued)		
	2.14 Charge Algorithm Verification	Clause 6.11, IEEE 1725:2021	R4
	2.15 Timer Fault	Clause 6.12, IEEE 1725:2021	R4
	2.16 Communication Fault	Clause 6.13, IEEE 1725:2021	R4
	2.17 Initiation of Charging Above Specified Voltage Threshold	Clause 6.15, IEEE 1725:2021	R4
	2.18 Initiation of Charging Below Specified Voltage Threshold	Clause 6.16, IEEE 1725:2021	R4
	2.19 Overdischarge Protection	Clause 6.17, IEEE 1725:2021	R4
	2.20 Impact Drop height: 1000 mm, 1500 mm	Clause 6.4, TCO for notebooks Clause 6.3, TCO for tablets, and smartphones	R4
	Drop height: 450 mm	Clause 5, IEC 60068-2-31	
	2.21 Discharge Performance at 20 C	Clause 7.3.1, IEC 61960-3:2017 Clause 7.3.3, IEC 61960-3:2017	R4
	2.22 Discharge Performance at Low Temperature	Clause 7.3.2, IEC 61960-3:2017	R4
	2.23 Charge (Capacity) retention capability	Clause 7.4, IEC 61960-3:2017	R4
	2.24 Charge (capacity) recovery after long term storage	Clause 7.5, IEC 61960-3:2017	R4



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code		
Mobile Phone Batteries Laptop, Notebook, Portable Computer Batteries (continued)	2 Environmental Tests (non explosive items) and associated Electrical and Teardown Tests (continued)				
	2.24 Endurance in cycles			Clause 7.6, IEC 61960-3:2017 Clause 6.5, TCO for notebooks Clause 6.4, TCO for smartphones, tablets	R4
	2.25 Internal resistance			Clause 7.7, IEC 61960-3:2017 Clause 6.5, TCO for notebooks Clause 6.4, TCO for smartphones, tablets	R4
	2.26 Product durability			Clause 6.4, TCO for notebooks Clause 6.3, TCO for tablets, and smartphones	R4
	Low temperature High temperature			Clause 6, IEC 60068-2-1 Clause 6, IEC 60068-2-2	R4
2.27 ESD	Clause 6.20, 7.3, IEEE 1725:2021	R4			



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Smartphone Batteries	<p>3 Measurement of Battery Lifetime for Smartphones and Smartwatches</p> <p>3.1 Total Available Energy (TAE)</p> <p>3.2.1 Gaming</p> <p>3.2.2 Compose, Send, Receive, Read SMS Message.</p> <p>3.2.3 Compose, Send, Receive, Read Email Message.</p> <p>3.2.4 Home Screen Display On.</p> <p>3.2.5 Audio Streaming/Music Playback.</p> <p>3.2.6 Video Streaming.</p> <p>3.2.7 Voice Call</p> <p>3.2.8 Web browsing</p> <p>3.2.9 Standby.</p> <p>3.2.10 Location Services</p>	CTIA Battery Life Test Plan, version 2.2	R4
WLAN equipment	<p>4 Wi-Fi system Interoperability</p>	<p>Wi-Fi CERTIFIED Wi-Fi Direct Test Plan v1.10</p> <p>Wi-Fi CERTIFIED Protected Management Frames Test Plan Version 1.8</p>	R4



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
Digital Terrestrial and Cable Television Receivers and Recorders	5. Digital Television Receiver Testing (continued) 5.2 SI/PSI	Malaysia: MCMC MTSFB TC T011:2024 MCMC MTSFB TC T004:2022 Ghana: Minimum requirements for Receivers of Free to Air Digital terrestrial Television (DTT) in Ghana using Ghana SI/PSI Test Suite	R4
		NorDig Unified Test plan, v.2.6.0 NorDig Unified Test Plan for Integrated Receiver Decoders Part II SI/PSI Testing Sections: - 2.5(MPEG2 Demultiplexer) - 2.6(Video) - 2.7(Audio) - 2.8(Teletext and subtitling) - 2.9(Interface and Signal Levels) - 2.10(Interfaces for Conditional Access) - 2.12(Performance) - 2.13(Service Information) - 2.14(Navigator) - 2.15(PVR Functionality)	R4
		Thailand: Technical standards for digital terrestrial television receivers NBTC BS 4002-2560 (2017) NBTC BS 4002-2565 (2022) Indonesia: Regulation Of The Minister Of Communication And Information In The Republic Of Indonesia Number 4:2019 Samoa: Receiver Specification For Digital Terrestrial Television Samoa February 2016 Vietnam: QCVN 63:2020/BTTTT	R4



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
Digital Terrestrial and Cable Television Receivers and Recorders	5. Digital Television Receiver Testing (continued) 5.3 Over the Air Download (OAD)	Malaysia: MCMC MTSFB TC T011:2024 MCMC MTSFB TC T004:2022 NorDig Unified Test plan, v. 2.6.0 NorDig Unified Test Specification for Integrated Receivers/Decoders Part II Section 2.11.Overair Download Testing. Thailand: Technical standards for digital terrestrial television receivers NBTC BS 4002-2560 (2017) NBTC BS 4002-2565 (2022) Indonesia: Regulation Of The Minister Of Communication And Informatics of The Republic Of Indonesia Number 4:2019 Vietnam: QCVN 63:2020/BTTTT	R4
	5.4 Early Warning systems (EWS)	Indonesia: Regulation of the Minister Of Communication and Informatics of The Republic of Indonesia Number 3:2014	R4
	5.5 System Software update (SSU)	Samoa: Receiver Specification For Digital Terrestrial Television Samoa February 2016	
	5.6 Hybrid Broadcast (HbbTV)	Malaysia: MCMC MTSFB TC T011:2024 MCMC MTSFB TC T004:2022 MCMC MTSFB TC G002:2020	R4



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Materials/Products tested	Type of test/Properties measured/Range of measurement	Standard specifications/ Equipment/Techniques used	Location Code
Digital Terrestrial TV Broadcast Receivers	5. Digital Television Receiver Testing (continued) 5.7 Wanted signal power I/C Ratio Blocking Level Overload Measurement	EN 303 340 V1.1.2 Clauses, 4.2.3, 4.2.4, 4.2.5, 4.2.6. EN 303 340 V1.2.1 Clauses, 4.2.3, 4.2.4, 4.2.5, 4.2.6.	R4
Satellite broadcast reception equipment	5.8 Adjacent signal selectivity Dynamic range	ETSI EN 303 372-2 v1.2.1	R4
END			